

## Notice of References Cited

	Application/Control f	Applicant(s)/Pate	nt Under	
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	Examiner	Art Unit		
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,178,419	01-2001	Legh-Smith et al.	707/6
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## NON-PATENT DOCUMENTS

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